Wednesday, July 15, 2015 - Afternoon Session

1:00 – 1:30 PM  
**ON-SITE REGISTRATION**

1:30 PM – 3:00 PM  
**WELCOME SESSION & KEYNOTE**

- Welcome Remarks – General Chair: Steve Tilden, Tilden Consulting
- 2014 Best Paper Award – Ben Brown, Xcerra
- Program Review – Program Chair: Rick Marshall, Cascade Microtech

1:30 – 1:35 PM  
**KEYNOTE: “How the Era of the IoT will Impact the Semiconductor & Cloud Markets”**

Kaivan Karimi – VP & GM of Wireless Solutions, Atmel, Inc.

**Keynote biography:** Kaivan Karimi is the Vice President & GM of Wireless Solutions at Atmel Corporation, currently overseeing the development of wireless connectivity solutions for IoT applications, with special focus on Edge Node system solutions. Kaivan brings over two decades of experience working in cellular wireless, connectivity, networking, sensors, and MCU semiconductor market, with a unique system level perspective spanning the technologies needed to make IoT a reality. Kaivan holds graduate degrees in Engineering (MSEE) & Business (MBA), and is an industry subject matter expert on all topics IoT, regularly speaking at forums, authoring papers and blogs addressing the relevant topic.

Prior to joining Atmel, Kaivan was Executive Director, Global Strategy and Business Development at Freescale Semiconductor, driving the IoT gateways technology and product requirements, and all company-wide IoT related activities.

2:45 PM – 3:00 PM  
**BREAK**

3:00 PM – 4:00 PM  
**SESSION 1: Wireless Test in the IoT Era**

- Session Chair: Ajay Khoche, Smart Connected Systems

3:00 – 3:20  
1.1 Dropping the Dime on Low Cost RF Test
- John Shelley, Xcerra

3:20 – 3:40  
1.2 Developing a Low Cost Test Solution for RF SoCs
- Paul Berndt, Cypress Semiconductor

3:40 – 4:00  
1.3 Second Generation Production ATE Solution for Microwave and Millimeter Wave Automotive Radar
- Devin Morris, Roos Instruments

4:00 PM – 5:00 PM  
**Panel Session 1: "What Does RF Test Look Like in Five Years?"**

Future Solutions for Lowering the Cost of Transceiver Tests

- **Moderator:** Mark Roos – Roos Instruments
- **Panelists:** John Shelley – Xcerra  
  Gerard John – Amkor  
  Brad Robbins – LitePoint  
  Paul Berndt – Cypress Semiconductor

**RECEPTION WITH POSTER SESSION**
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<th>Time</th>
<th>Reception with Poster Session: Evening Drinks &amp; Appetizers</th>
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| 5:00 PM – 6:30 PM | **Poster 1:** Virtual Test and Test Description Language for Mixed Signal, two disappointing topics in our industry, WHY?  
Thomas Burger, AMS  
**Poster 2:** RITdb-based Messaging Architecture  
Mark Roos, Roos Instruments  
**Poster 3:** What is TEMS? And what can it do for you?  
Keith Thomas, Teradyne Inc.  
**Poster 4:** ATE Information Portal: A collection of data and analytics from tester inventory to performance.  
Nelson Magdaleno & Stacy Ajouri, Texas Instruments  
**Poster 5:** Status update of IEEE P1838 3D-die stacking standard  
T.M. Mak, GLOBALFOUNDARIES  
**Poster 6:** ITRS – Test Working Group  
Dave Armstrong - Advantest |
Thursday, July 16, 2015 – Morning Session

7:30 – 8:00 AM  ON-SITE REGISTRATION

8:00 AM - 9:00 AM  INVITED SPEAKER

“The LTE Era: Innovation Through Evolution, The wireless transformation from smart to genius and beyond…”
Brad Shaffer – Senior Analyst, Mobile Electronics, IHS Technology

Invited Speaker Biography: Brad Shaffer is a senior analyst with the IHS semiconductors in mobile electronics team. Brad conducts research and analysis on the mobile handset RF components market and continually tracks the competitive landscape of the greater wireless semiconductor market.

Prior to joining IHS, Brad worked as a research and data analyst for NPD In-Stat. His research area spanned the company’s coverage of networking including WLAN, Broadband CPE, and Ethernet. As a data analyst, Brad supported the centralization and standardization of the company’s information assets. He was responsible for the development and support of forecast models and analytical tools across the organization. Prior to that, he held multiple positions in accounting and economic analysis.

Brad received a Bachelor of Science in Accountancy from the WP Carey School of Business at Arizona State University, graduating with honors.

9:00 – 9:10 AM  BREAK

9:10 AM - 10:30 AM  SESSION 2: Test Flows and Tools for Today’s New Cost Challenges
Session Chair: Dave Armstrong, Advantest

9:10 – 9:30  2.1 Lean Kanban for Test Development
• Jonathan Boyce & Shawn Ironmonger, AMD

9:30 – 9:50  2.2 Partitioning Test between Massively Parallel DFT Tester and ATE and using a Baggage Handling System to reduce cost and complexity of test
• Alberto Salamone, ELES Semiconductor

9:50 – 10:10  2.3 What does “Big Data” really mean for Manufacturing Test?
• Michael Schuldenfrei, Optimal+

10:10 – 10:30  2.4 Applying Data Providence and Security to RITdb
• Mark Roos, Roos Instruments

10:30 AM – 10:45 AM  BREAK
10:45 AM – 11:45 AM  INVITED SPEAKER

“Sensor Test Challenges and Outlook”

Thomas Burger – Director Test Development, Sr. Manager Test Technology, ams AG

Invited Speaker Biography: Thomas Burger leads Test Development & Technology at AMS in Graz Austria, where he lectures for Measurement & Control Engineering and is expert for EU funded projects. He is also a certified court & surveyor for electronics, measurement & control engineering.

Prior to joining AMS, Thomas was at Phillips Semiconductor where he worked in the Identification Business RFID, NFC, contact-and contactless Smartcards in different functions such as supplier Manager RFID, Test Development Manager for Identification and prior to that was at AMS test in mixed-signal ASICs for Industrial, Consumer, Medical and Automotive product lines.

Thomas received an MSc in Electronics and Control Engineering in 1990 and then his PhD in 1999, both from Technical University of Graz, Austria.

11:45 AM – 1:00 PM  NETWORKING LUNCH

Thursday, July 16, 2015 – Afternoon Session

1:00 PM – 2:20 PM  SESSION 3: Advanced Packaging, Advanced Test Challenges

Session Chair: Amy Leong, FormFactor

1.00 – 1:20  3.1 High Performance HBM Known Good Stack Testing

- Marc Loranger, FormFactor

1:20 – 1:40  3.2 WLP Post-Singulation Test Handling Trends and Challenges

- Serge Kuenzli, COHU/Ismeca

1:40 – 2:00  3.3 Automated Testing for Bare Die-to-Die Stacks

- Jörg Kiesewetter, Cascade Microtech

2:00 – 2:20  3.4 Final Test Solution of WLCSP Devices

- Lawrie Wright, Xcerra

2:20 PM – 2:30 PM  BREAK

2:30 PM – 3:45 PM  Panel Session 2: "How Secure is Your Test Data, Really?"

Risks and Best Defenses Against Damaging Data Leaks

- Moderator: Stacy Ajouri, Texas Instruments
- Panelists: Ken Harris – PDF Solutions
- Andy Evans – Broadcom
- Mark Roos – Roos Instruments
- Gerard John – Amkor
- Mike Rodgers – Reach IPS

CLOSING REMARKS

3:45 – 4:00  Closing Remarks – General Chair: Steve Tilden – Tilden Consulting